International
IOR Rectifier

HF10D120ACE

Hexfred Die in Wafer Form

1200V
$I_{F(nom)}$=5A
$V_{F(typ)}$= 1.59V @ $I_{F(nom)}$ @ 25°C
Motor Control Antiparallel Diode
125mm Wafer

Features

- GEN3 Hexfred Technology
- Low V_F
- Low I_{RR}
- Low t_{RR}
- Soft Reverse Recovery

Benefits

- Benchmark Efficiency for Motor Control Applications
- Rugged Transient Performance
- Low EMI
- Excellent Current Sharing in Parallel Operation
- Qualified for Industrial Market

Electrical Characteristics (Wafer Form)

Parameter	Description	Guaranteed (min, max)	Test Conditions
V_F	Forward Voltage Drop	1.44V min, 1.82V max	I_F = 1.875A, T_J = 25°C
BV_R	Reverse Breakdown Voltage	1200V min	T_J = 25°C, I_R = 100µA
I_{RM}	Reverse Leakage Current	1.25µA max	T_J = 25°C, V_R = 1200V

Mechanical Data

Nominal Backmetal Composition, (Thickness)	Cr- Ni - Ag, (1kA - 4kA - 6kA)
Nominal Front Metal Composition, (Thickness)	99% Al/1% Si, (3µm)
Dimensions	0.90" x 0.90"
Wafer Diameter	125mm, with std. < 100 > flat
Wafer Thickness, Tolerance	310µm, +/-15µm
Relevant Die Mechanical Dwg. Number	01 - 5523
Minimum Street Width	100µm
Reject Ink Dot Size	0.25mm diameter minimum
Ink Dot Location	Consistent throughout same wafer lot
Recommended Storage Environment	Store in original container, in dessicated nitrogen, with no contamination
Recommended Die Attach Conditions	For optimum electrical results, die attach temperature should not exceed 300°C

Die Outline

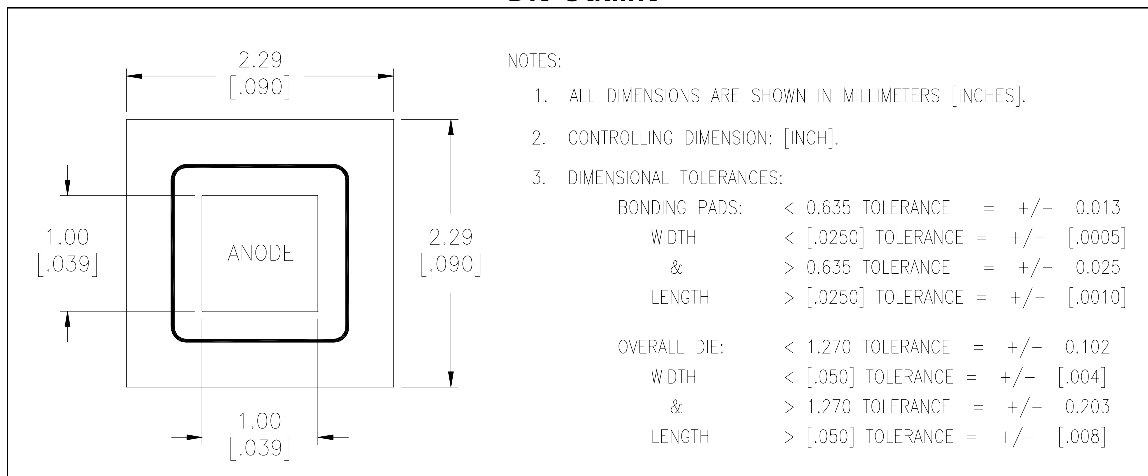

Fig.1 - Typical Diode Recovery
V_{CC} = 600V; Rg = 47Ω; T_J = 125°C;
L = 200µH; Driver = IRGB5B120K

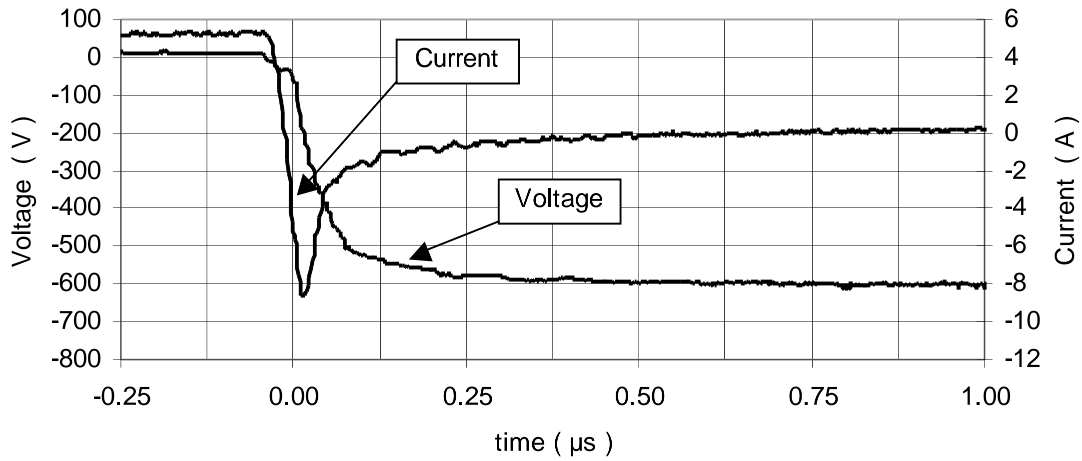

Fig.2 - Typical Diode Forward Characteristic
tp=300µs

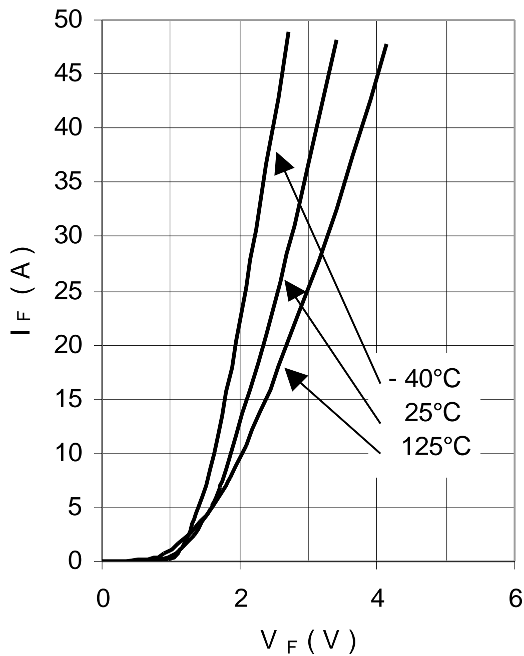

Fig. 3 - Diode Recovery Circuit